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This study provides physical characterization of 30 cell lines from the Physical Sciences Oncology Center (PS-OC) Network Bioresource Core Facility (PBCF) using atomic force microscopy.

The goal of the study was to assess the effect of cell line growth substrate on the physical properties of individual cells from the cell lines. The study's assay used atomic force microscopy (AFM) to measure the deflection of a cantilever upon contact with the cells. In this study, the test samples represent 30 cell lines grown on 7 different substrates. Measurements were done in triplicate. Control samples were not included in this study.

Download dataset at <ftp://caftpdc.nci.nih.gov/psondcc/PhysicalCharacterization/AFM.2/>